

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**In re Application of Applicants:**

Date: June 25, 2008

Beaman et al.

Group Art Unit: 2829

Serial No.: 09/382,834

Examiner: V. P. Nguyen

Filed: August 25, 1999

Docket No.: YO993-028BX

For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS,  
TEST PROBE AND METHODS OF USE THEREOF

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

PLEASE DO NOT ENTER

10/09/08

/VN/

## AMENDMENT

In response to Office Action dated May 14, 2008, please consider the following:

Amendments to the claims begin on page 2 of this paper.

Remarks begin on page 35 of this paper.